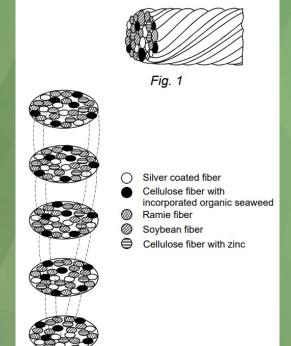


# Imaging and EDS on silver and zinc coated textile sample

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#### Sample

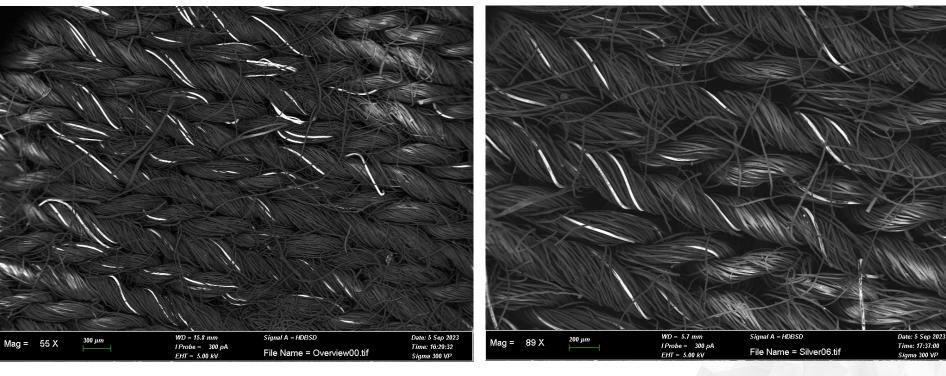
Piece of textile was delivered 2023-09-06 to Swerim

Following analysis was performed:

- SEM imaging from the top of sample
- Cross section SEM and EDS analysis from the cross section after gold sputtering (2 min exposure, aiming for ~ 20 nm thick layer)
- SEM/EDS analysis were performed using Sigma 300VP SEM instrument with 6kV acceleration voltage and 300pA current.

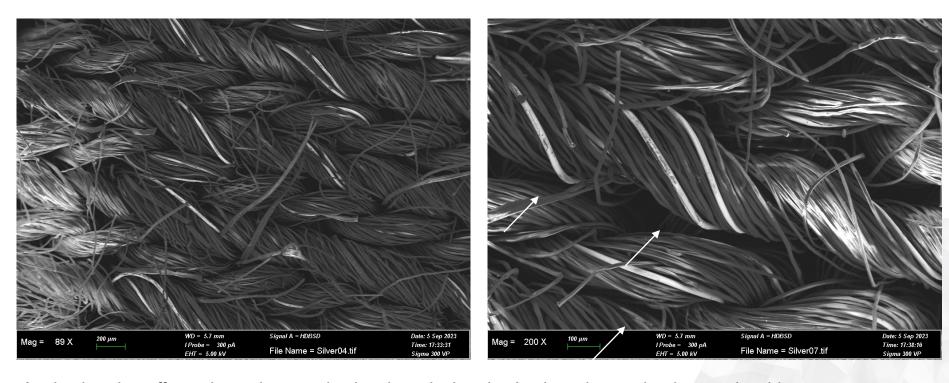


#### **Overview from the top**



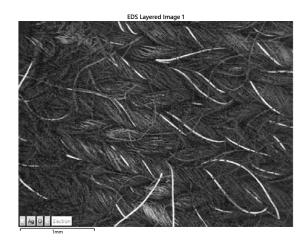
Some charging effect due to low concentration of conductive threads (Ag), but the Ag threads are clearly seen in white. Zn coated fibers did not show, this is probably due the thin Zn-coating. Zn also have a lower atom weight.

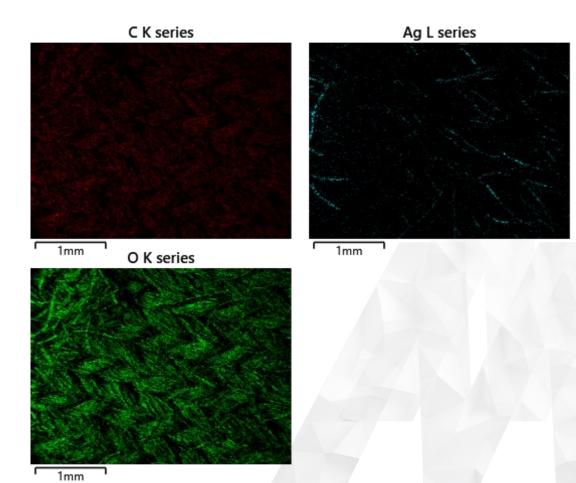
#### **Overview images**



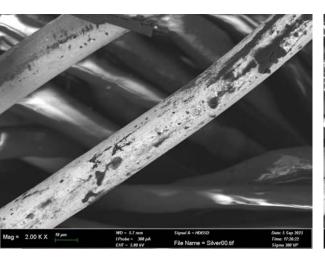
Again charging effects due to low conductive threads, but the Ag threads are clearly seen in white. The silver layer seems to be thin and complete coverage have not been obtained.

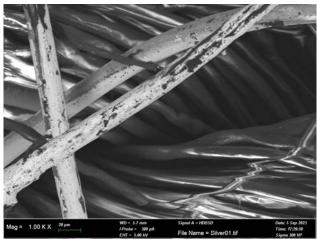
## **EDS** analysis

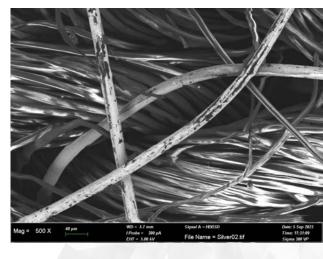




#### Some of the silver threads



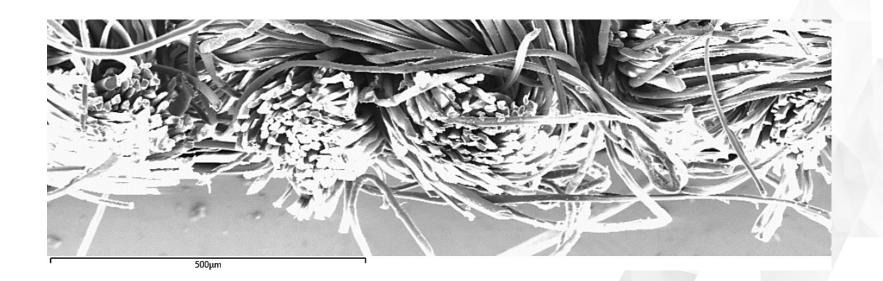




#### **Cross section analysis**

To avoid the charging effect, after cutting the sample with razor blade, half od the sample was coated with gold for easier imaging.

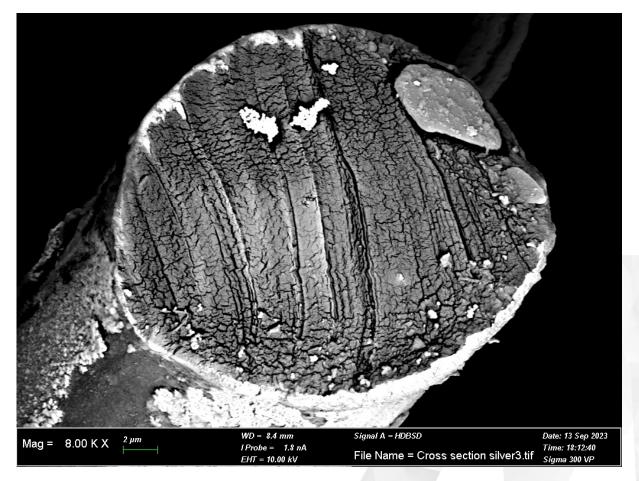




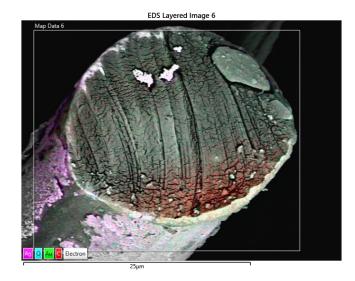
#### **Cross section**

Thread with silver coating Thickness of Ag coating ≤1µm

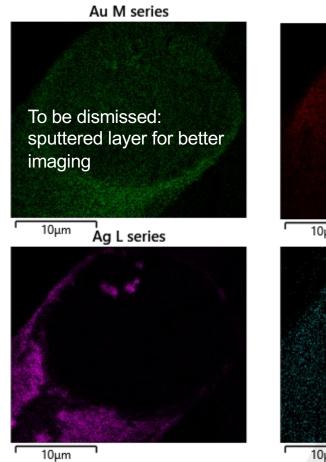
This SEM image was captured using 10kV acceleration voltage and 1.8 nA current.

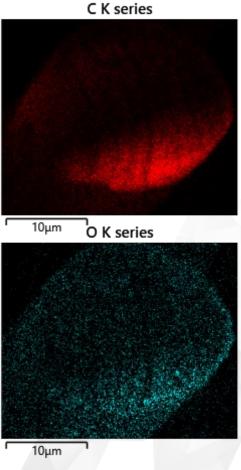


#### **EDS** analysis

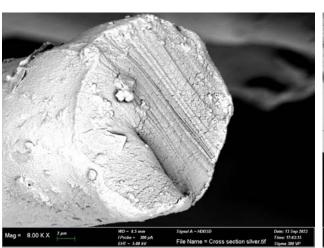


This EDS image was captured using 10kV acceleration voltage and 1.8 nA current.





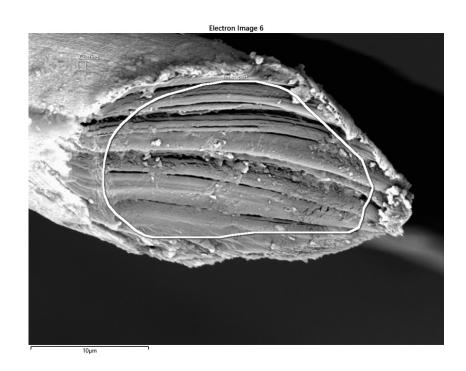
#### More images of threads







### **Point analysis using EDS**



Label	С	0		Fe	Ag	Total
Inner part	77	<sup>7</sup> ,1	14,6	7,7	0,5	100
Coating	26	3,3	4,4	2,8	66,5	100

Values are presented in wt.%



### **Exploring for Zn threads**

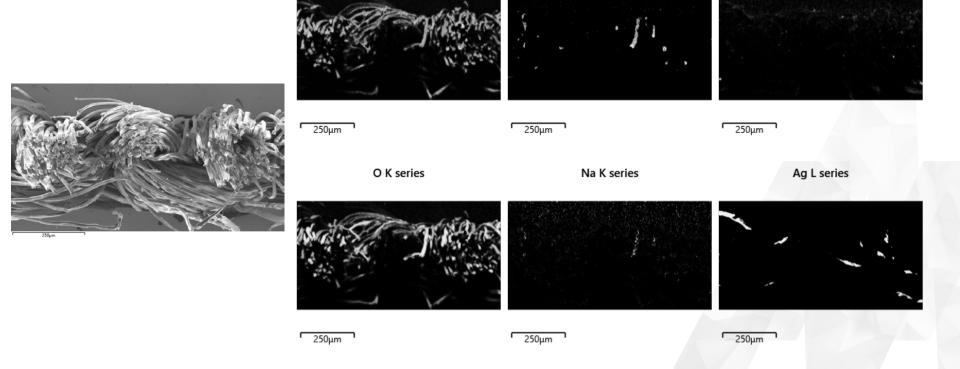
#### Sample preparation

Zn signal was found to be very weak. The contrast was not enough for imaging with back scattered detector. Long EDS mapping (overnight) showed clear Zn signal.

Sample was coated with C from the top and cross section. Carbon sputtering was performed using Leica EM ACE600 with a carbon thread source, working distance 30 mm, Double Pulse mode, aiming at 5 nm thick carbon layer.

EDS scan was performed using Sigma 300VP SEM instrument with 6kV acceleration voltage and 350pA current.

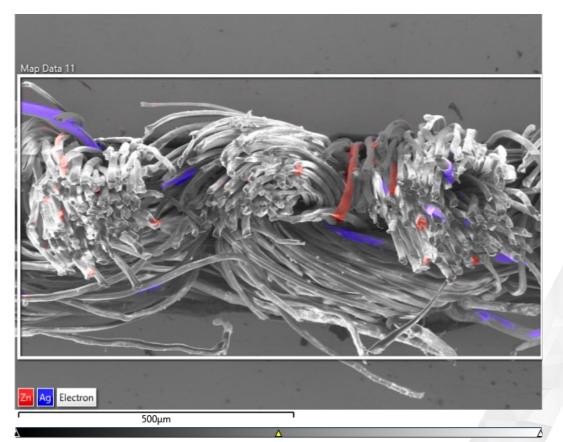
# EDS results from cross section of sample CK series Zn L series



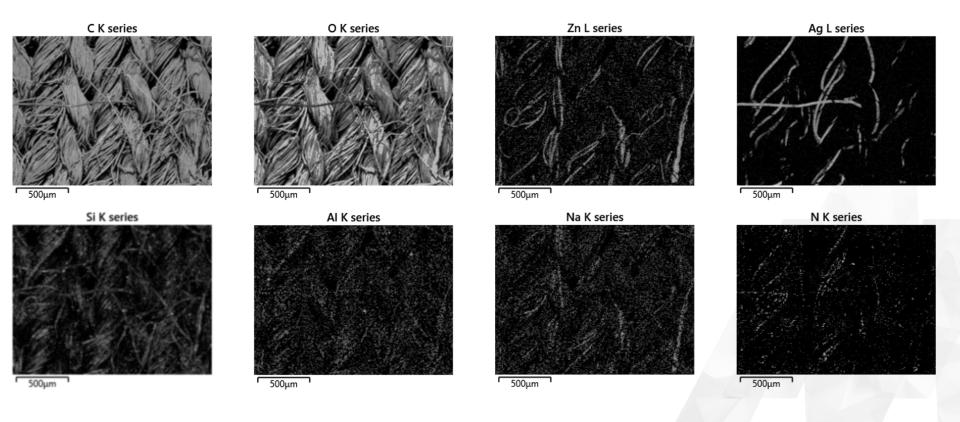
Si K series

**Cross section EDS overlayed with SEM** 

image



#### **EDS** results from top of sample



### **EDS** results from top of sample

